

# Nanocatalyst Fabrication Using a Stencil Mask



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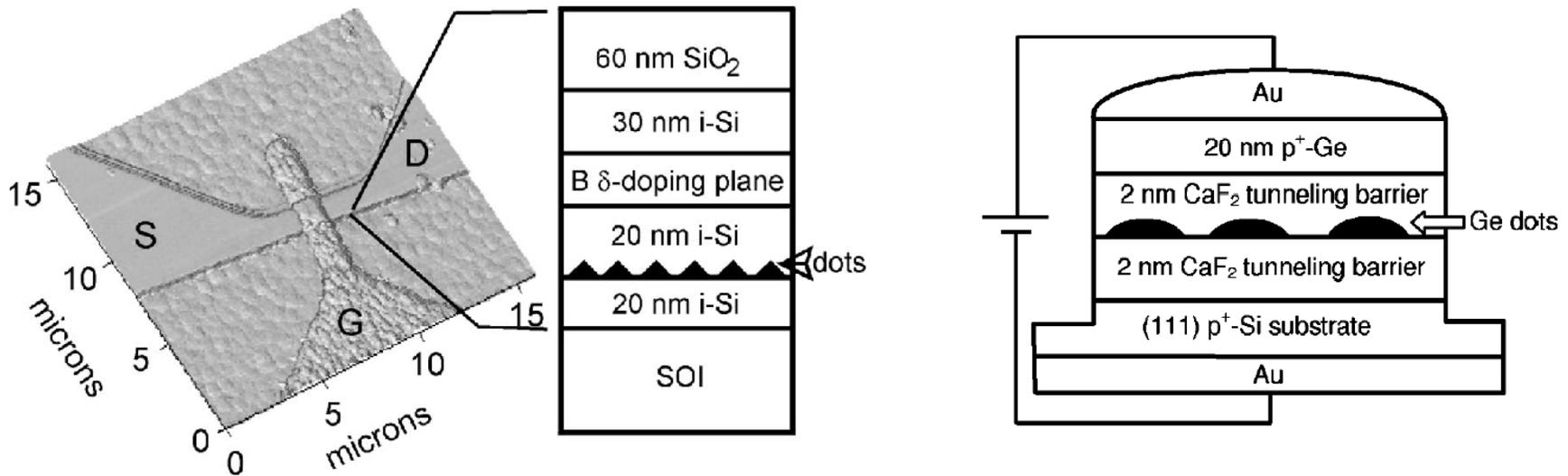
# Outline



- 1. Introduction and Background**
- 2. Vapor-Liquid-Solid Growth Mechanism**
- 3. Nanofabrication Procedure**
  - a. Stencil Mask Design**
  - b. Exposures and Etching**
- 4. Summary**

# Introduction

## Quantum Dots for MOS-FETs and resonant tunneling diodes



**GeSi quantum-dot metal–oxide–semiconductor field-effect transistor**, Appl. Phys. Lett. **81**, A. I. Yakimov, A. V. Dvurechenskii, V. V. Kirienko, and A. I. Nikiforov

**Growth and characterization of CaF<sub>2</sub> / GeSi / CaF<sub>2</sub> / Si — 111 — quantum dots for resonant tunneling diodes operating at room temperature**, Appl. Phys. Lett. **80**, A. I. Yakimov, A. S. Derjabin, et al.

# Vapor-liquid-solid synthesis of Ge islands



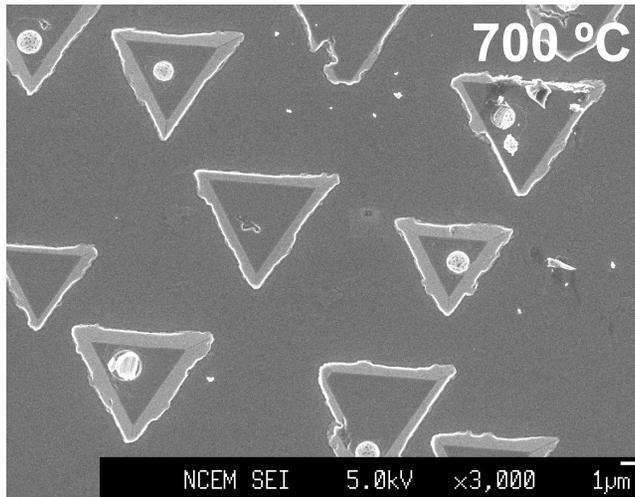
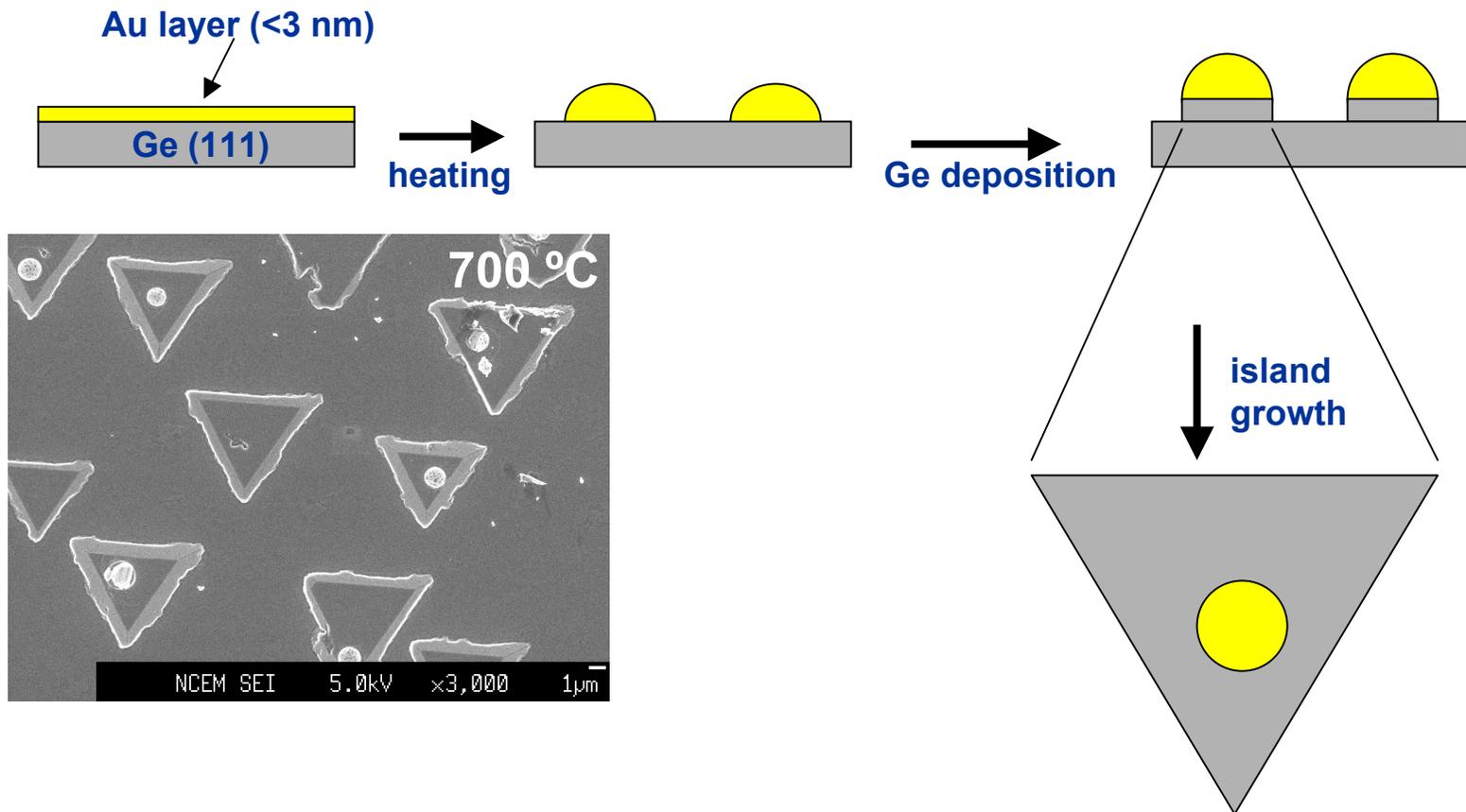
Increase the number of growth parameters to control the size, density and arrangement of grown semiconductor islands



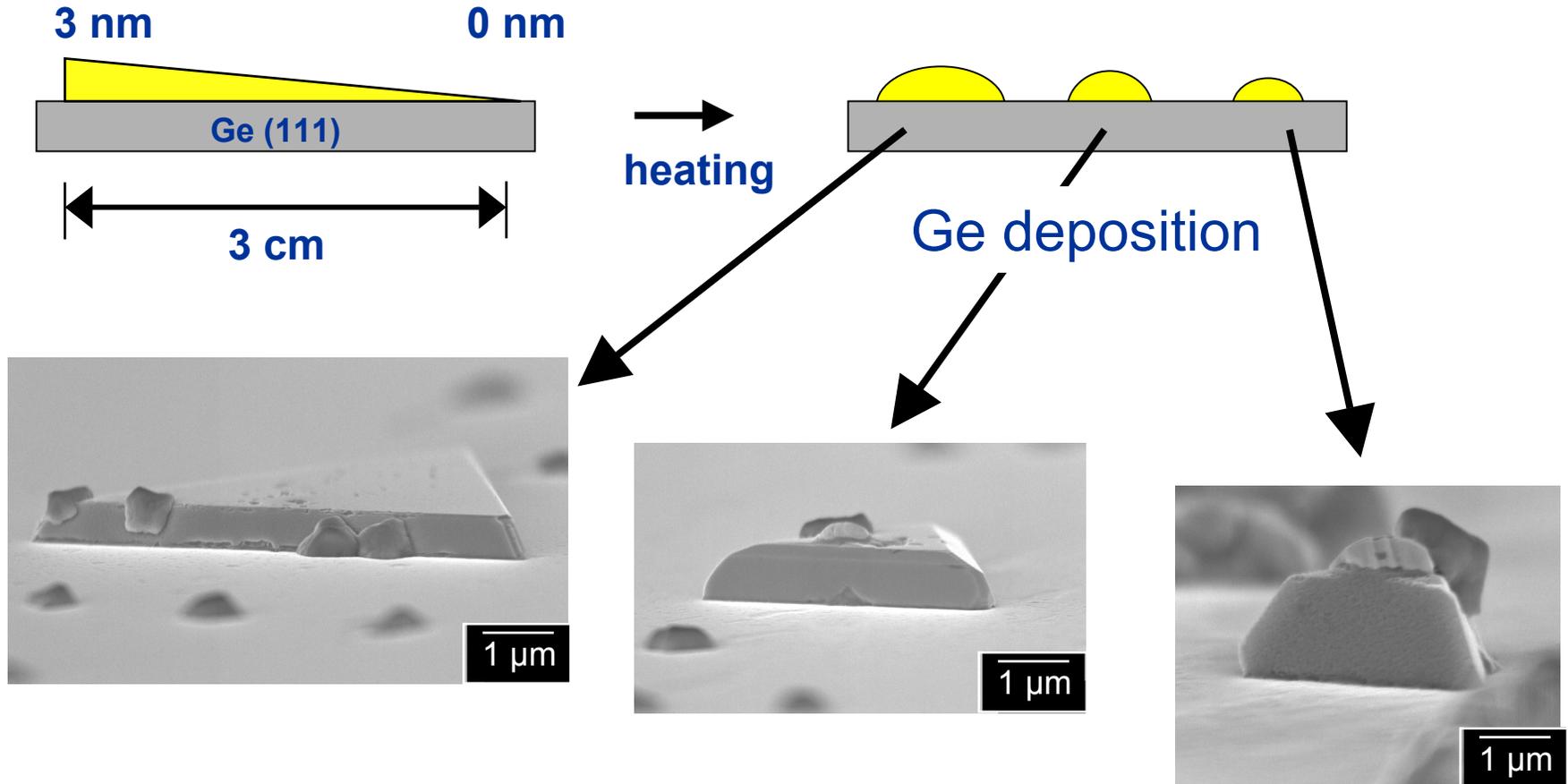
Droplet-induced island nucleation and growth by a vapor-liquid-solid approach

# Ge island synthesis

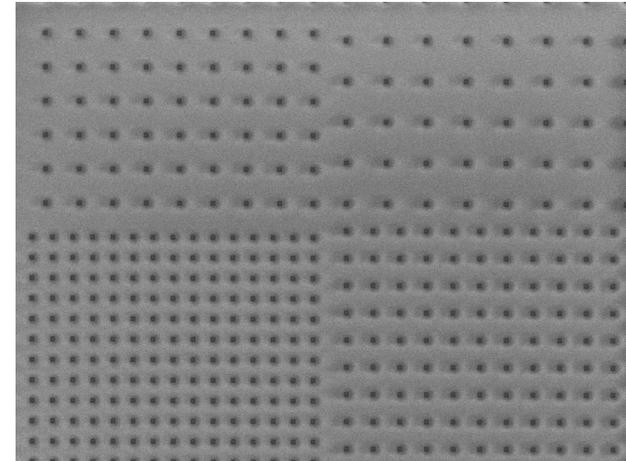
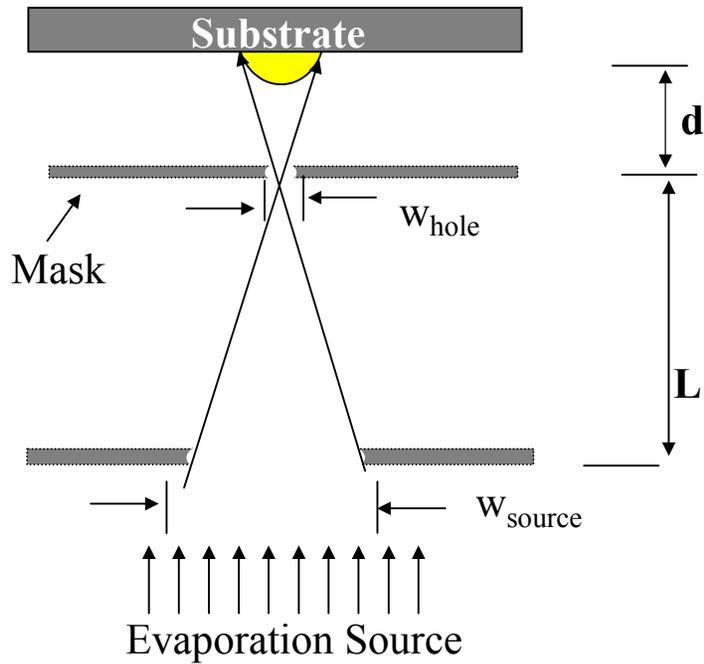
- Island nucleation on Ge (111) at Au-Ge eutectic droplets
- Solid-source molecular beam epitaxy



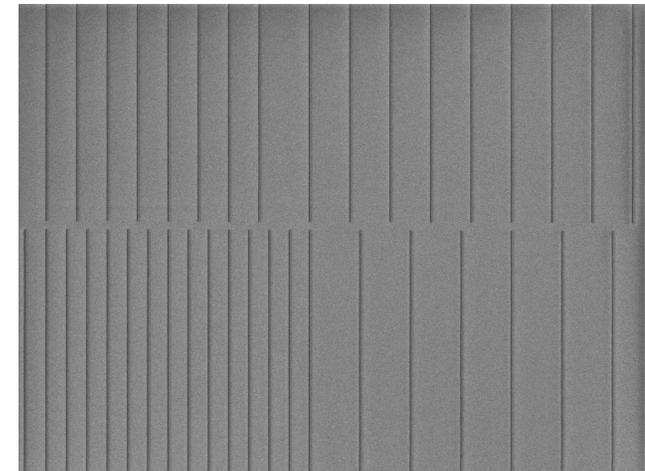
# Island Size Versus Au Layer Thickness



# Stencil Mask Design



Features: 25nm – 300nm



$$w_{dot} \approx w_{hole} + \left( \frac{d}{L} \right) w_{source}$$

# Wafer Processing



## Wafer Database

1900

Wafer ID

Fri., May. 9, 2003

Started (date)

Fri., May. 9, 2003

Deactivated (date: mm/dd/yyyy)

Bruce

Operator

UCBerkeley

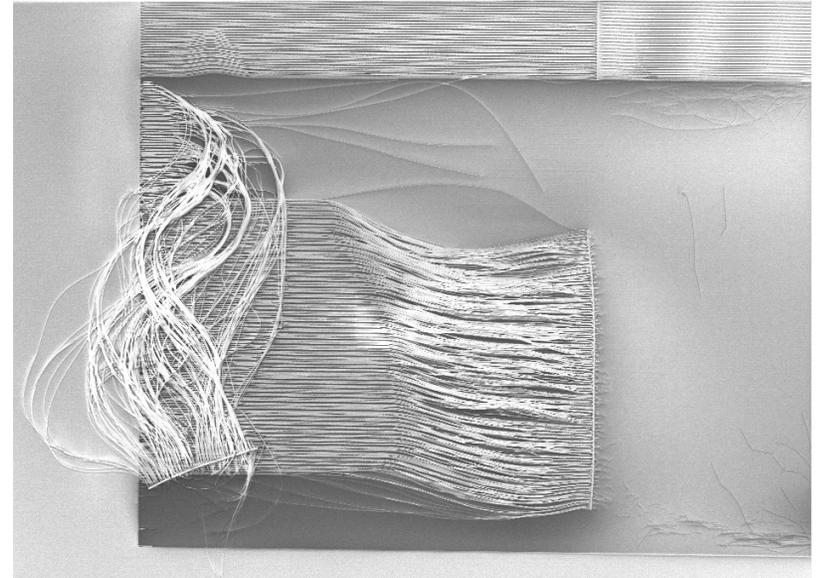
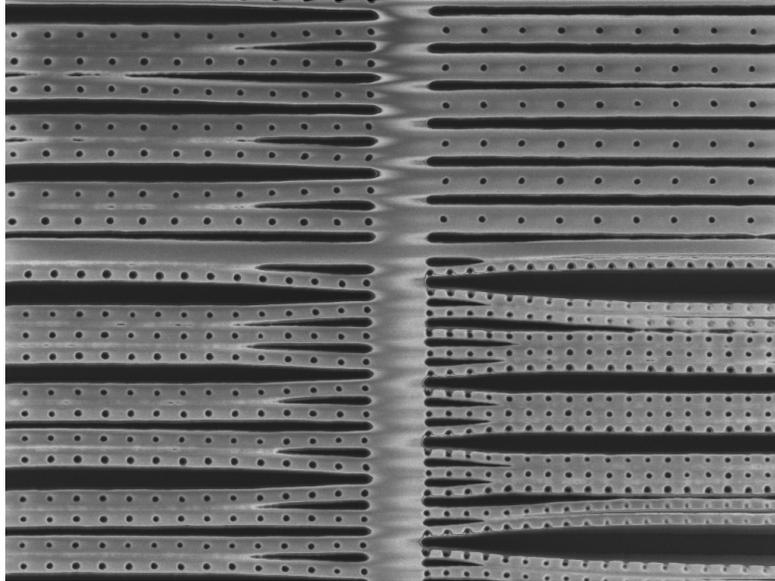
Customer

Instruction sheet

### Ge Au catalysed nucleation and growth experiment

1. Spin 11.6% KRS-XE @ 1000 rpm
2. PAB 110 C, 3mins
3. Expose with GEISLES3, 75  $\mu\text{C}/\text{cm}^2$
4. Develop LDD26W 75s
5. O<sub>2</sub> descum 20s
6. Nitride etch

# 1<sup>st</sup> Exposure

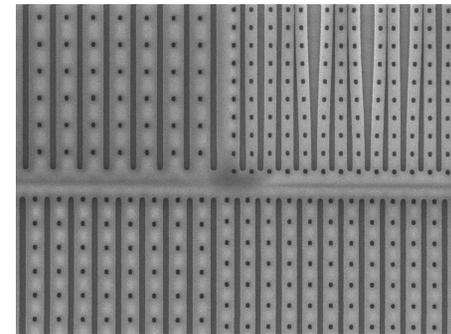
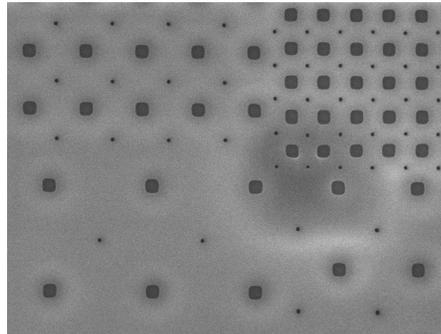
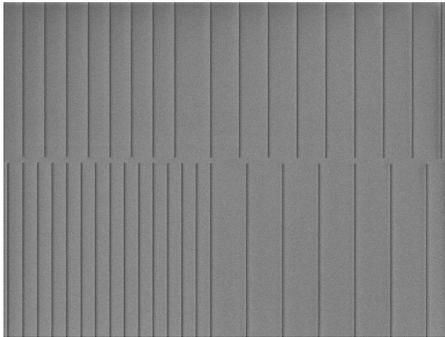


- Line spacings were too close
- Upper end of dose range was too large

# 2<sup>nd</sup> Exposure



- Examples of the final patterned features for the SiN windows.



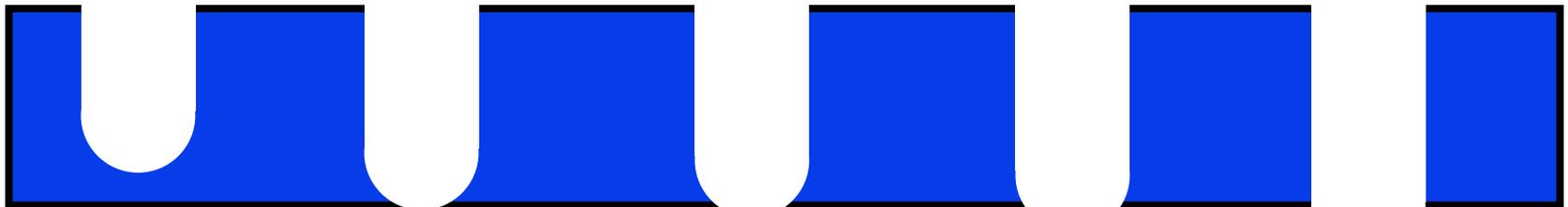
- Etch rates for SiN and developed KRS

	Etch Rate: SiN	Etch Rate: KRS
$\text{CHF}_4/\text{O}_2$	~80A/min	~90A/min
$\text{SF}_6$ (large features)	~350A/min	~300A/min
$\text{SF}_6$ (small features)	>500A/min	~300A/min

# Membrane Exposure



- **Exposed and Developed SiN membranes**
- **We expect the size to be small than the patterned feature**
- **An Isotropic etch will make a bowl shaped feature in the membrane**



# Summary



- We have designed a variety of features to be patterned on SiN membrane windows.
- We have begun a process that can produce stencil mask features smaller than the patterned features.
- The etch mask will be used for patterning metal features on Ge and Si wafers.
- The resulting evaporated structures will be used in a VLS process to study the equilibrium shape evolution of Ge islands.

# Acknowledgements



**Thanks to Alex Liddle,  
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